## **Description**

The device is intended to take 1 or 2 reference clocks, select between them, using a pin or register selection and generate up to 8 outputs that may be the same as the reference frequency or integer-divider versions of it.

The 8P79818 supports two output banks, each with its own divider and power supply. All outputs in one bank would generate the same output frequency, but each output can be individually controlled for output type, output enable or even powered-off.

The device supports a serial port for configuration of the parameters while in operation. The serial port can be selected to use the I<sup>2</sup>C or SPI protocol. After power-up, all outputs will come up in LVDS mode and may be programmed to other configurations over the serial port. Outputs may be enabled or disabled under control of the OE input pin.

The device can operate over the -40°C to +85°C temperature range.

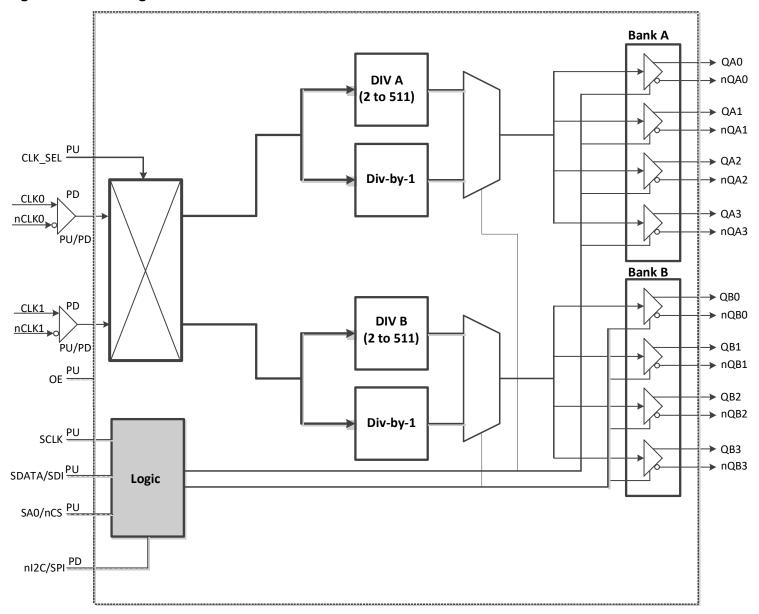
#### **Features**

- Two differential inputs support LVPECL, LVDS, HCSL or LVCMOS reference clocks
  - Accepts input frequencies ranging from 1PPS (1Hz) to 700MHz
- Select which of the two input clocks is to be used as the reference clock for which divider via pin or register selection
  - Switchover will not generate any runt clock pulses on the output
- Generates eight differential outputs or eight LVCMOS outputs, Bank A only
  - Differential outputs selectable as LVPECL, LVDS, CML or HCSL
  - Differential outputs support frequencies from 1PPS to 700MHz
  - LVCMOS outputs support frequencies from 1PPS to 200MHz
  - LVCMOS outputs in the same pair may be inverted or in-phase relative to one another
- Outputs arranged in 2 banks of 4 outputs each
  - Each bank supports a separate power supply of 3.3V, 2.5V or 1.8V
  - 1.5V output voltage is also supported for LVCMOS, Bank A only
  - One divider per output bank, supporting divide ratios of 2...511 or divider bypass
- Output enable control pin
  - Output enable or disable will not cause any runt pulses
- Register programmable via I<sup>2</sup>C / SPI serial port
  - Individual output enables, output type selection and output power-down control bits supported
  - Input mux selection control bit
- Core voltage supply of 3.3V, 2.5V or 1.8V
- -40°C to +85°C ambient operating temperature
- Lead-free (RoHS 6) packaging



## **Block Diagram**

Figure 1: Block Diagram

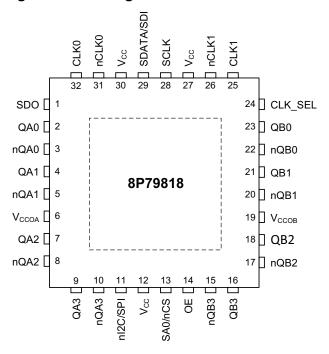


8P79818 transistor count: 33,394



## **Pin Assignment**

Figure 2: Pin Assignments for 5mm x 5mm 32-Lead VFQFN Package (Top View)



## **Pin Description and Characteristic Tables**

**Table 1: Pin Description** 

Number	Name	Type <sup>[a]</sup>	Description
1	SDO	Output	SPI mode data output signal. Unused in I <sup>2</sup> C mode.
2	QA0	Output	Positive differential clock output. Included in Bank A. Refer to Output Drivers section for details.
3	nQA0	Output	Negative differential clock output. Included in Bank A. Refer to Output Drivers section for details.
4	QA1	Output	Positive differential clock output. Included in Bank A. Refer to Output Drivers section for details.
5	nQA1	Output	Negative differential clock output. Included in Bank A. Refer to Output Drivers section for details.
6	V <sub>CCOA</sub>	Power	Output supply for output Bank A.
7	QA2	Output	Positive differential clock output. Included in Bank A. Refer to Output Drivers section for details.
8	nQA2	Output	Negative differential clock output. Included in Bank A. Refer to Output Drivers section for details.
9	QA3	Output	Positive differential clock output. Included in Bank A. Refer to Output Drivers section for details.
10	nQA3	Output	Negative differential clock output. Included in Bank A. Refer to Output Drivers section for details.
			Select protocol for serial port:
11	nl2C/SPI	Input (PD)	0 = I <sup>2</sup> C mode
			1 = SPI mode
12	V <sub>CC</sub>	Power	Core logic supply.
13	SA0/nCS	Input (PU)	SPI chip select input (active low) in SPI mode. Base address bit 0 in I <sup>2</sup> C mode.



### **Table 1: Pin Description (Cont.)**

			Master output enable control					
		1	waster output enable control					
14	OE	Input (PU)	0 = All outputs high-impedance					
			1 = All outputs enabled or disabled under control of register bits					
15	nQB3	Output	Negative differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
16	QB3	Output	Positive differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
17	nQB2	Output	Negative differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
18	QB2	Output	Positive differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
19	V <sub>CCOB</sub>	Power	Output supply for output Bank B.					
20	nQB1	Output	Negative differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
21	QB1	Output	Positive differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
22	nQB0	Output	Negative differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
23	QB0	Output	Positive differential clock output. Included in Bank B. Refer to Output Drivers section for details.					
24	CLK_SEL	Input (PU)	Input clock selection control pin. This pin may be disabled by register control, but if enabled (default) its function is:  0 = CLK0 is selected					
			1 = CLK1 is selected					
25	CLK1	Input (PD)	Non-inverting differential clock input.					
26	nCLK1	Input (PU/ PD)	Inverting differential clock input. V <sub>CC</sub> /2 when left floating (set by the internal pull-up and pull-down resistors).					
27	V <sub>CC</sub>	Power	Core logic supply.					
28	SCLK	Input (PU)	Serial port input clock for either SPI or I <sup>2</sup> C mode.					
29	SDATA/ SDI	Input/Output (PU) Input (PU)	In I <sup>2</sup> C mode, this is the bi-directional data signal for the serial port In SPI mode, this is the data input signal.					
30	V <sub>CC</sub>	Power	Core logic supply.					
31	nCLK0	Input (PU/ PD)	Inverting differential clock input. $V_{\rm CC}/2$ when left floating (set by the internal pull-up and pull-down resistors).					
32	CLK0	Input (PD)	Non-inverting differential clock input.					
EP	V <sub>EE</sub>	Ground	Must be connected to ground (GND).					

a. Pull-up (PU) and pull-down (PD) resistors are indicated in parentheses. *Pullup* and *Pulldown* refer to internal input resistors. See Table 10, *DC Input/ Output Characteristics*, for typical values.



## **Principles of Operation**

#### **Input Selection**

The 8P79818 supports two input references: CLK0 and CLK1 that may be driven with differential or single-ended clock signals. Either or both may be used as the source frequency for either output divider under control of the CLK. SEL input pin or under register control.

The CLK\_SEL pin is the default selection mechanism and selects whether both dividers are driven by the CLK0, nCLK0 input (CLK\_SEL = Low) or by the CLK1, nCLK1 input (CLK\_SEL = High).

If the user enables register control via the SEL\_REG control bit, then there are 4 selection options available as shown in Table 2.

Table 2: Input Selection Register Control (SEL\_REG = 1)

CLK_S	EL [1:0]	Description
0	0	Divider A & B both driven from CLK0
0	1	Divider A driven from CLK1 & Divider B driven from CLK0
1	0	Divider A driven from CLK0 & Divider B driven from CLK1
1	1	Divider A & B both driven from CLK1

#### **Output Dividers**

Each bank of outputs has its own divider. All outputs in the same bank will be driven by that divider and so will all have the same frequency. Divider A supplies the QA output bank and Divider B supplies the QB output bank. Each divider is capable of being driven by the same or a different input frequency. Each divider can pass that input frequency directly to the outputs or to divide it by any integer from 2 up to 511.

## **Output Drivers**

The QA[0:3] and QB[0:3] clock outputs are provided with register-controlled output drivers. By selecting the output drive type in the appropriate register, any of these outputs can support LVCMOS, LVPECL, CML, HCSL or LVDS logic levels.

CML operation supports both a 400mV peak-peak swing and an 800mV peak-peak swing selection.

The operating voltage ranges of each output bank is determined by its independent output power pin ( $V_{CCOA}$  or  $V_{CCOB}$ ). Output voltage levels of 1.8V, 2.5V or 3.3V are supported for differential operation and LVCMOS operation. In addition, LVCMOS output operation supports 1.5V  $V_{CCO}$ .

A global OE input pin is provided. If the OE pin is negated (Low), then all outputs will be in a high-impedance state. If the OE pin is asserted (High), then each output will behave as indicated by its individual register enable bit. Using the global OE pin to enable or disable outputs will not result in any 'runt' clock pulses on the outputs.

Each output bank may be enabled or disabled using the SYNC\_DISx register bit. Using these bits to enable or disable outputs will not result in any 'runt' clock pulses on the outputs.

Individual outputs within a bank may be enabled or disabled using the DIS\_Qxm register bits. These bits however may result in 'runt' pulses on the outputs if the output is otherwise enabled, so it is recommended that the entire bank be disabled via the appropriate SYNC\_DISx register bit while an individual output is being enabled using the DIS\_Qxm bit to avoid a possible 'runt' pulse on the output. If 'runt' pulses are not a concern, then the DIS\_Qxm bits may be used directly.

#### **LVCMOS Operation**

When a given output is configured to provide LVCMOS levels, then both the Q and nQ outputs will toggle at the selected output frequency. All the previously described configuration and control apply equally to both outputs. Frequency, voltage levels and enable / disable status apply to both the Q and nQ pins.

When configured as LVCMOS, the Q & nQ outputs can be selected to be phase-aligned with each other or inverted relative to one another. Phase-aligned outputs will have increased simultaneous switching currents which can negatively affect phase noise performance and power consumption. It is recommended that use of this selection be kept to a minimum.



#### **Power-Saving Modes**

To allow the device to consume the least power possible for a given application, the following functions are included under register control:

- Any unused output can be individually powered-off.
- If either bank is completely unused, all logic, including the dividers for that bank may be completely powered-off.
- Clock gating on logic that is not being used.

#### **Device Start-up Behavior**

The device will power-up with all outputs enabled in LVDS mode and all dividers bypassed.

## **Serial Control Port Description**

#### **Serial Control Port Configuration Description**

The device has a serial control port capable of responding as a slave in an I<sup>2</sup>C or SPI compatible configuration, to allow access to any of the internal registers for device programming or examination of internal status. All registers are configured to have default values. See the specifics for each register for details. Selection of I<sup>2</sup>C versus SPI protocol will be done via the nI2C/SPI input pin.

#### **SPI Mode Operation**

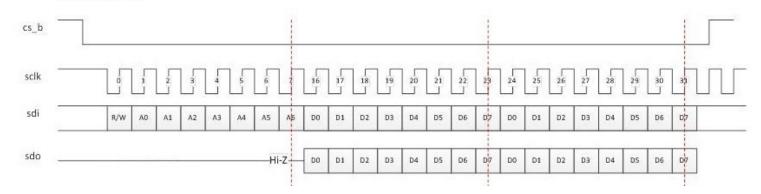
SPI mode can be enabled via pin selection from power-up. The following information assumes SPI mode has been selected.

In a read operation (R/W bit is '1'), data on SDO will be clocked out on the falling edge of SCLK.

In a write operation (R/W bit is '0'), data on SDI will be clocked in on the rising edge of SCLK.

#### Figure 3: SPI Read Sequencing Diagram

Read (LSB first)



During SPI Write operations, the user may continue to hold nCS low and provide further bytes of data for up to a total of 16 bytes in a single block write. Data is written directly into the appropriate register as it is received.

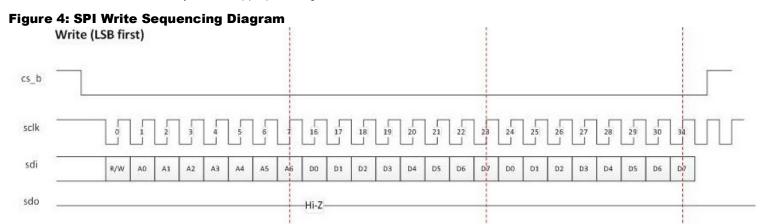


Figure 5: SPI Read/Write Timing Diagram

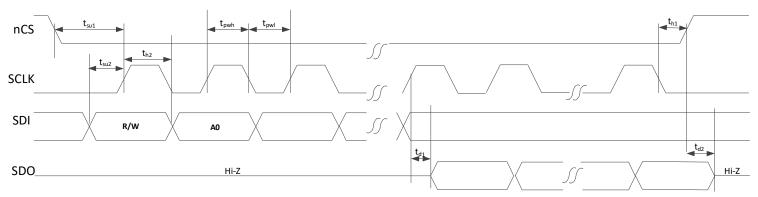


Table 3: Timing Characteristics in SPI Mode<sup>[a]</sup>

Symbol	Parameter	Min	Тур	Max	Unit
t <sub>pw</sub>	SCLK Period	20			ns
t <sub>pw1</sub>	SCLK Pulse Width Low	8			ns
t <sub>pw2</sub>	SCLK Pulse Width High	8			ns
t <sub>su1</sub>	Valid nCS to SCLK Rising Setup Time	10			ns
t <sub>h1</sub>	Valid nCS After Valid SCLK Hold Time (CLKE = 0/1)	10			ns
t <sub>su2</sub>	Valid SDI to SCLK Rising Setup Time	5			ns
t <sub>h2</sub>	Valid SDI after valid SCLK Hold Time	5			ns
t <sub>d1</sub>	SCLK falling (rising in CLKE = 1 case) to Valid Data Delay Time			5	ns
t <sub>d2</sub>	nCS rising edge to SDO High Impedance Delay Time			10	ns
t <sub>csh</sub>	Time between Consecutive Read-Read or Read-Write Accesses (nCS rising edge to nCS falling edge)	20			ns

a. Specifications guaranteed by design and characterization.

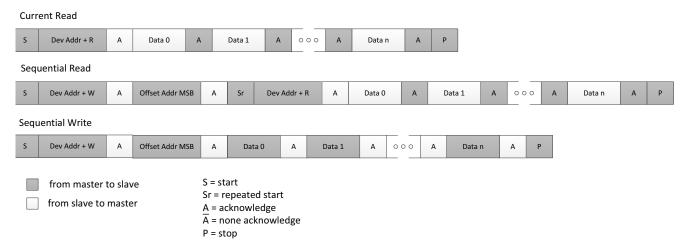


## I<sup>2</sup>C Mode Operation

The I<sup>2</sup>C interface is designed to fully support v1.0 of the I<sup>2</sup>C specification for *normal* and *fast* mode operation. The device acts as a slave device on the I<sup>2</sup>C bus at 100kHz or 400kHz using an address of 110110x (binary), where the value of 'x' is set by the SA0/nCS input pin. The interface accepts byte-oriented block write and block read operations. One address byte specifies the register address of the byte position of the first register to write or read. Data bytes (registers) are accessed in sequential order from the lowest to the highest byte (most significant bit first). Read and write block transfers can be stopped after any complete byte transfer. During a write operation, data will be written to the registers directly as each byte is received.

For full electrical I<sup>2</sup>C compliance, it is recommended to use external pull-up resistors for SDATA and SCLK. The internal pull-up resistors have a size of  $51k\Omega$  typical.

Figure 6: Slave Read and Write Cycle Sequencing



## **Register Descriptions**

#### **Table 4: Register Blocks**

Register Ranges Offset (Hex)	Register Block Description
0 – 1	Device control
2 – 5	Bank A control
6 – 9	Bank B control
A – B	Reserved
C – F	Divide ratios



### **Table 5: Device Control Register Bit Field Locations**

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
0	CLKMODE	CLK_SEL[1:0]		SEL_REG	Rsvd	Rsvd	Rsvd	DIV_SYNC
1	BKA_Vx	BKB_Vx	SYNC_DISA	SYNC_DISB	PWR_DNA	PWR_DNB	DIS_DIVA	DIS_DIVB

Bit Field Name	Field Type	Default Value	Description
			Clock switchover mode selection:
CLKMODE	R/W	0b	0 = Forced clock switch (may result in glitches as clocks switch)
CERWODE	17/44	ob	1 = Glitch-less clock switch (may remain on original clock source if that source is no longer toggling)
			Select which input clock is to be used as the reference clock. These bits are only in effect when SEL_REG = 1:
CLK_SEL[1:0]	R/W	00b	00 = CLK0, nCLK0 input drives both Divider A & Divider B 01 = CLK1, nCLK1 input drives Divider A & CLK0, nCLK0 drives Divider B 10 = CLK0, nCLK0 input drives Divider A & CLK1, nCLK1 drives Divider B 11 = CLK1, nCLK1 input drives both Divider A & Divider B
			Determines if input clock selection is to be performed by pin or register:
SEL_REG	R/W	0b	0 = CLK_SEL input pin controls reference selection mux 1 = CLK_SEL register bits controls reference selection mux
Rsvd	R/W	_	Reserved. Always write '0' to this bit location. Read values are not defined.
			Divider synchronization control:
DIV_SYNC	R/W	0b	0 = Dividers running normally 1 = Dividers in reset (output clocks halted) 1–>0 transition on this bit will synchronize the Bank A & Bank B output dividers
			Bank A voltage setting for optimal performance:
BKA_Vx	R/W	0b	0 = V <sub>CCOA</sub> is 3.3V
			1 = V <sub>CCOA</sub> is 2.5V,1.8V, and 1.5V
			Bank B voltage setting for optimal performance:
BKB_Vx	R/W	0b	$0 = V_{CCOB}$ is $3.3V$
			1 = V <sub>CCOB</sub> is 2.5V,1.8V
			Glitch-free output enable bit for Bank A outputs:
SYNC_DISA	SYNC_DISA R/W		0 = Outputs in Bank A are enabled glitch-lessly as indicated by their individual DIS_QAm bits 1 = All outputs for Bank A are high-impedance
			Glitch-free output enable bit for Bank B outputs:
SYNC_DISB	R/W	0b	0 = Outputs in Bank B are enabled glitch-lessly as indicated by their individual DIS_QBm bits 1 = All outputs for Bank B are high-impedance



Bit Field Name	Field Type	Default Value	Description	
			Power-down control for Bank A outputs:  0 = All outputs for Bank A are powered (SYNC DISA should be 1 when	
PWR_DNA	R/W	0b	0b	powering-up the bank to prevent glitches on the output)  1 = All outputs in Bank A are powered-off
			Power-down control for Bank B outputs:	
PWR_DNB	B R/W	0b	0 = All outputs for Bank B are powered (SYNC_DISB should be 1 when powering-up the bank to prevent glitches on the output) 1 = All outputs in Bank B are powered-off	
			Power-down output divider for Bank A (DIVA must be set to 000h to bypass):	
DIS_DIVA	R/W	0b	0 = Output divider for Bank A is powered	
			1 = Output divider for Bank A is powered-down	
			Power-down output divider for Bank B (DIVB must be set to 000h to bypass):	
DIS_DIVB	R/W	0b	0 = Output divider for Bank B is powered 1 = Output divider for Bank B is powered-down	



### **Table 6: Bank A Control Register Bit Field Locations**

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
2		Rsvd		TERM_A	QA_POL3	QA_POL2	QA_POL1	QA_POL0
3	Rs	svd	MODE_QA3[2:0]			MODE_QA2[2:0]		
4	Rsvd		MODE_QA1[2:0]		]	MODE_QA0[2:0]		
5	DIS_QA3 DIS_QA2		DIS_QA1	DIS_QA0		Rs	svd	

Bit Field Name	Field Type	Default Value	Description
TERM_A	R/W	0b	Indicates termination used on Bank A outputs when HCSL mode is selected: $0=33\Omega/\ 50\Omega$ $1=50\Omega$
QA_POLm	R/W	0h	Output polarity selection for output pair nQAm, QAm in LVCMOS mode:  0 = nQAm pin is inverted relative to QAm pin when in LVCMOS mode  1 = nQAm and QAm pins are in-phase when in LVCMOS mode
MODE_QAm[2:0]	R/W	010b	Output driver mode of operation for output pair QAm, nQAm:  000 = high-impedance 001 = LVPECL 010 = LVDS (default) 011 = LVCMOS 100 = HCSL 101 = CML 400mV swing 110 = CML 800mV swing 111 = Reserved
DIS_QAm	R/W	0b	Disable output pair QAm, nQAm:  0 = Output pair QAm, nQAm is enabled (disable output bank using SYNC_DISA to prevent runt pulses when enabling)  1 = Output pair QAm, nQAm is powered-down
Rsvd	R/W	_	Reserved. Always write 0 to this bit location. Read values are not defined.



### **Table 7: Bank B Control Register Bit Field Locations**

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0
6		Rsvd		TERM_B	Rsvd	Rsvd	Rsvd	Rsvd
7	Rs	vd	MODE_QB3[2:0]			MODE_QB2[2:0]		
8	Rsvd		MODE_QB1[2:0]		]	MODE_QB0[2:0]		]
9	DIS_QB3 DIS_QB2		DIS_QB1	DIS_QB0		Rs	svd	

Bit Field Name	Field Type	Default Value	Description
TERM_B	R/W	0b	Indicates termination used on Bank B outputs when HCSL mode is selected: $0=33\Omega/50\Omega$ $1=50\Omega$
MODE_QBm[2:0]	R/W	010b	Output driver mode of operation for output pair QBm, nQBm:  000 = high-impedance 001 = LVPECL 010 = LVDS (default) 011 = Rsvd 100 = HCSL 101 = CML 400mV swing 110 = CML 800mV swing 111 = Reserved
DIS_QBm	R/W	0b	Disable output pair QBm, nQBm:  0 = Output pair QBm, nQBm is enabled (disable output bank using SYNC_DISB to prevent runt pulses when enabling)  1 = Output pair QBm, nQBm is powered-down
Rsvd	R/W	_	Reserved. Always write 0 to this bit location. Read values are not defined.



### **Table 8: Divide Ratio Register Field Locations**

Address (Hex)	D7	D6	D5	D4	D3	D2	D1	D0			
С		DIVA[7:0]									
D				DIVE	B[7:0]						
E			Rs	svd			DIVB[8]	DIVA[8]			
F				Rs	vd						

Bit Field Name	Field Type	Default Value	Description
			Divider ratio for Bank A outputs:
DIVA[8:0]	R/W	000h	00h - 01h = Bypass divider and pass reference clock directly to the Bank A outputs
			02h — 1FFh = ratio to be used by the A divider is value written here. For example writing a 4 in this field will results in a divide ratio of 4 being used.
			Divider ratio for Bank B outputs:
DIVB[8:0]	R/W	000h	00h - 01h = Bypass divider and pass reference clock directly to the Bank B outputs
			02h – 1FFh = ratio to be used by the B divider is value written here. For example writing a 4 in this field will results in a divide ratio of 4 being used.
Rsvd	R/W	_	Reserved. Always write 0 to this bit location. Read values are not defined.



## **Absolute Maximum Ratings**

The absolute maximum ratings are stress ratings only. Stresses greater than those listed below can cause permanent damage to the device. Functional operation of the 8P79818 at absolute maximum ratings is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

**Table 9: Absolute Maximum Ratings** 

Item	Rating
Supply voltage, V <sub>CCX</sub> <sup>[a]</sup> to GND	3.6V
Inputs SCLK, SDATA/SDI, SA0/nCS, CLK_SEL, CLK0, nCLK0, CLK1, nCLK1, OE, nl2C/SPI	-0.5V to 3.6V
Outputs, I <sub>O</sub> QA[0:3], nQA[0:3], QB[0:3], nQB[0:3]	
Continuous current	40mA
Surge current	60mA
Outputs, V <sub>O</sub> QA[0:3], nQA[0:3], QB[0:3], nQB[0:3]	-0.5V to 3.6V
Outputs, V <sub>O</sub> SDO, SDATA/SDI	-0.5V to 3.6V
Operating junction temperature	125°C
Storage temperature, T <sub>STG</sub>	-65°C to 150°C
Lead temperature (Soldering, 10s)	+260°C

a.  $V_{CCx}$  denotes  $V_{CC}$ ,  $V_{CCOA}$ , or  $V_{CCOB}$ .



## **DC Characteristics**

### **Table 10: DC Input/ Output Characteristics**

Symbol		Paramete	r	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>in</sub>	Input capacit	ance				0.5		pF
		LVPECL				0.8		pF
		LVDS	QA[0:3], nQA[0:3]	\		1.2		pF
		CML 400mV	QB[0:3], nQB[0:3]	$V_{CCOX}^{[a]} = 3.465V \text{ or } 2.625V$		0.48		pF
	Power	CML 800mV				0.44		pF
0	dissipation	LVCMOS	Bank A	V <sub>CCOA</sub> = 3.465V or 2.625V		2.33		pF
$C_PD$	capacitance	LVPECL				1.4		pF
	(per output)	LVDS	QA[0:3], nQA[0:3]	V - 1.90V		1.5		pF
		CML 400mV	QB[0:3], nQB[0:3]	V <sub>CCOX</sub> = 1.89V		0.53		pF
		CML 800mV				0.3		pF
		LVCMOS	Bank A	V <sub>CCOA</sub> = 1.89V or 1.575V		2.1		pF
R <sub>PULLUP</sub>	Input pull-up	resistor				51		kΩ
R <sub>PULLDOWN</sub>	Input pull-dov	wn resistor				51		kΩ
				LVCMOS output type selected $V_{CCOA} = 3.3V \pm 5\%$		24		Ω
D	Output impos	lanca	QA[3:0], nQA[3:0]	LVCMOS output type selected V <sub>CCOA</sub> = 2.5V <u>+</u> 5%		15		Ω
NOUT	R <sub>OUT</sub> Output impedance	ianc <del>e</del>	αλ[3.0], Παλ[3.0]	LVCMOS output type selected V <sub>CCOA</sub> = 1.8V±5%		26		Ω
				LVCMOS output type selected V <sub>CCOA</sub> = 1.5V <u>+</u> 5%		46		Ω

a.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}$ .



## Supply Voltage Characteristics,

Table 11: Power Supply Characteristics,  $V_{CC}$  = 3.3V ±5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to +85°C<sup>[a], [b], [c]</sup>

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Core supply voltage		3.135		3.465	V
V <sub>CCOA</sub> , V <sub>CCOB</sub>	Output supply voltage		1.71		V <sub>CC</sub>	V
I <sub>CC</sub>	Core supply current			23	26	mA
I <sub>CCOA</sub> +	Output supply current	DIV-by-1		157	177	mA
I <sub>CCOB</sub>	Output supply current	DIV A = DIV B = 2		125	140	mA
I <sub>EE</sub>	Power supply current			183	206	mA

a. Internal dynamic switching current at maximum f<sub>OUT</sub> is included.

Table 12: Power Supply Characteristics,  $V_{CC}$  = 2.5V ±5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to +85°C<sup>[a], [b], [c]</sup>

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Core supply voltage		2.375		2.625	V
V <sub>CCOA</sub> , V <sub>CCOB</sub>	Output supply voltage		1.71		V <sub>CC</sub>	V
I <sub>CC</sub>	Core supply current			18	20	mA
I <sub>CCOA</sub> +	Output cumply ourront	DIV-by-1		156	175	mA
I <sub>CCOB</sub>	Output supply current	DIV A = DIV B = 2		124	139	mA
I <sub>EE</sub>	Power supply current			177	199	mA

a. Internal dynamic switching current at maximum f<sub>OUT</sub> is included.

b. All outputs configured for LVEPCL logic levels and not terminated.

c.  $V_{CC} \ge V_{CCOA}$  and  $V_{CCOB}$ .

b. All outputs configured for LVEPCL logic levels and not terminated.

c.  $V_{CC} \ge V_{CCOA}$  and  $V_{CCOB}$ .



Table 13: Power Supply Characteristics,  $V_{CC}$  = 1.8V ±5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to +85°C<sup>[a], [b], [c]</sup>

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Core supply voltage		1.71		1.89	V
V <sub>CCOA</sub> , V <sub>CCOB</sub>	Output supply voltage		1.71		V <sub>CC</sub>	V
I <sub>CC</sub>	Core supply current			14	16	mA
I <sub>CCOA</sub> +	Output supply current	DIV-by-1		143	160	mA
I <sub>CCOB</sub>	Output supply current	DIV A = DIV B = 2		117	132	mA
I <sub>EE</sub>	Power supply current			161	181	mA

- a. Internal dynamic switching current at maximum f<sub>OUT</sub> is included.
- b. All outputs configured for LVEPCL logic levels and not terminated.
- c.  $V_{CC} \ge V_{CCOA}$  and  $V_{CCOB}$ .

Table 14: Output Supply Current,  $V_{CC}$  = 3.3V, 2.5V or 1.8V,  $V_{EE}$  = 0V,  $T_A$  = 25°C<sup>[a], [b]</sup>

		Ø		V <sub>CCOx</sub> <sup>[d]</sup> = 3.3V			V <sub>CCOx</sub> <sup>[d]</sup> = 2.5V				V <sub>CCOx</sub> <sup>[d]</sup> = 1.8V				$V_{CCOx}^{[d]} = 1.5V$ $V_{CCOx}^{[d]} = 1.5V + 5\%$				
Symbol	Parameter <sup>[c]</sup>	Test Conditions	LVPECL	LVDS	HCSL	LVCMOS	CML	LVPECL	LVDS	HCSL	LVCMOS	CML (400mV)	LVPECL	LVDS	HCSL	LVCMOS	CML (400mV)	LVCMOS	Units
	Bank A output	V <sub>CC</sub> = 3.3V, T <sub>A</sub> = 25°C	76	96	73	119	60	75	96	67	92	58	68	87	66	72	53	60	mA
I <sub>CCOA</sub>	supply	V <sub>CC</sub> = 3.3V + 5%, T <sub>A</sub> = 85°C	88	114	87	149	70	88	113	85	111	67	80	104	78	86	63	71	mA
1	Bank B output	V <sub>CC</sub> = 3.3V, T <sub>A</sub> = 25°C	76	96	73	119	60	75	96	67	92	58	68	87	66	72	53	60	mA
Іссов	supply current	V <sub>CC</sub> = 3.3V, T <sub>A</sub> = 85°C	88	114	87	149	70	88	113	85	111	67	80	104	78	86	63	71	mA

- a. All outputs not terminated.
- b.  $V_{CC} \ge V_{CCOA}$  and  $V_{CCOB}$ .
- c. Internal dynamic switching current at maximum  $f_{\mbox{\scriptsize OUT}}$  is included.
- d.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}.$



### **DC Electrical Characteristics**

## Table 15: LVCMOS/LVTTL Control / Status Signals DC Characteristics, $V_{EE}$ = 0V, $T_A$ = -40°C to +85°C

Symbol		Parameter	Test Conditions	Minimum	Typical	Maximum	Units
			V <sub>CC</sub> = 3.3V	2.20		V <sub>CC</sub> +0.3	V
$V_{IH}$	Input high voltag	е	V <sub>CC</sub> = 2.5V	1.85		V <sub>CC</sub> +0.3	V
			V <sub>CC</sub> = 1.8V	1.25		V <sub>CC</sub> +0.3	V
			V <sub>CC</sub> = 3.3V	-0.3		0.8	V
$V_{IL}$	Input low voltage	)	V <sub>CC</sub> = 2.5V	-0.3		0.7	V
			V <sub>CC</sub> = 1.8V	-0.3		0.7	V
I <sub>IH</sub>	Input	SA0/nCS, SDATA/SDI, SCLK, CLK_SEL, OE	V <sub>CC</sub> = V <sub>IN</sub> = 3.465V, 2.625V or - 1.89V			5	μА
	high current	nI2C/SPI	- 1.097			150	μΑ
I <sub>IL</sub>	Input low current	SA0/nCS, SDATA/SDI, SCLK, CLK_SEL,OE	V <sub>CC</sub> = 3.465V, 2.625V or 1.89V,	-150			μΑ
	low current	nI2C/SPI	$-V_{IN} = 0V$	-5			μΑ
	0.1.1		$V_{CC} = 3.3V \pm 5\%, I_{OH} = -5mA$	2.6			V
$V_{OH}$	Output high voltage	SDATA/SDI, SDO	V <sub>CC</sub> = 2.5V ±5%, I <sub>OH</sub> = -5mA	1.8			V
	J.: 1 2112.g 3		V <sub>CC</sub> = 1.8V ±5%, I <sub>OH</sub> = -5mA				V
V <sub>OL</sub>	Output low voltage	SDATA/SDI, SDO	$V_{CC}$ = 3.3V ±5% or 2.5V ±5% or 1.8V ±5%, $I_{OL}$ = 5mA			0.5	V

# Table 16: Differential Input DC Characteristics, $V_{CC}$ = 3.3V±5%, 2.5V±5% or 1.8V±5%, $V_{EE}$ = 0V, $T_A$ = -40°C to +85°C

Symbol	Paran	neter	Test Conditions	Minimum	Typical	Maximum	Units
I <sub>IH</sub>	Input high current	CLKx, nCLKx <sup>[a]</sup>	V <sub>CC</sub> = V <sub>IN</sub> = 3.465V or 2.625V			150	μА
1	Input	CLKx <sup>[a]</sup>	V <sub>CC</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	<b>-</b> 5			μΑ
l IIL	low current	nCLKx <sup>[a]</sup>	V <sub>CC</sub> = 3.465V or 2.625V, V <sub>IN</sub> = 0V	-150			μΑ
V <sub>PP</sub>	Peak-to-peak volta	age <sup>[b]</sup>		0.15		1.3	V
V <sub>CMR</sub>	Common mode in	put voltage <sup>[b], [c]</sup>		0		V <sub>CC</sub>	V

a. CLKx denotes CLK0, CLK1. nCLKx denotes nCLK0, nCLK1.

b.  $V_{IL}$  should not be less than –0.3V.  $V_{IH}$  should not be higher than  $V_{CC}$ .

c. Common mode voltage is defined as the cross-point.



Table 17: LVPECL DC and AC Characteristics,  $V_{CC}$  = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%,  $V_{EE}$  = 0V,  $T_A$  = -40°C to +85°C

			$V_{CCOx}^{[a]} = 3.3V \pm 5\%$			$V_{CCOx}^{[a]} = 2.5V \pm 5\%$			$V_{CCOx}^{[a]} = 1.8V \pm 5\%$			
Symbol	Paramete	er	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Units
V <sub>OH</sub>	Output high voltage <sup>[b]</sup>	Qx, nQx <sup>[c]</sup>	V <sub>CCOx</sub> - 1.30		V <sub>CCOx</sub> - 0.80	V <sub>CCOx</sub> - 1.35		V <sub>CCOx</sub> - 0.80	V <sub>CCOx</sub> - 1.50		V <sub>CCOx</sub> - 0.90	V
V <sub>OL</sub>	Output low voltage	Qx, nQx <sup>[c]</sup>	V <sub>CCOx</sub> - 2.00		V <sub>CCOx</sub> - 1.75	V <sub>CCOx</sub> - 2.00		V <sub>CCOx</sub> - 1.75	V <sub>EE</sub>		0.25	V
V	Output voltage swing, f <sub>OUT</sub> < 500MHz	Qx, nQx <sup>[c]</sup>	0.5	0.8	1.2	0.5	0.8	1.2	0.35	0.6	1.0	V
V <sub>OUT</sub>	Output voltage swing, f <sub>OUT</sub> < 700MHz	Qx, nQx <sup>[c]</sup>	0.3	0.65	1.05	0.3	0.65	1.05	0.25	0.45	0.7	V

a.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}$ .

## Table 18: LVDS DC and AC Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{CCOA}$ = $V_{CCOB}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $T_A$ = -40°C to +85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OD</sub>	Differential output voltage	Qx, nQx <sup>[a]</sup>		247		480	mV
$\Delta V_{OD}$	V <sub>OD</sub> magnitude change	Qx, nQx <sup>[a]</sup>	Terminated $100\Omega$ across			50	mV
V <sub>OS</sub>	Offset voltage	Qx, nQx <sup>[a]</sup>	Qx and nQx	1.125		1.375	V
ΔV <sub>OS</sub>	V <sub>OS</sub> magnitude change	Qx, nQx <sup>[a]</sup>				50	mV

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

# Table 19: CML (400mV Swing) DC and AC Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{CCOA}$ = $V_{CCOB}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $T_A$ = -40°C to +85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OH</sub>	Output high voltage	Qx, nQx <sup>[a]</sup>	T	$V_{CCOx}^{[b]} - 0.10$		V <sub>CCOx</sub> [b]	V
V <sub>OL</sub>	Output low voltage	Qx, nQx <sup>[a]</sup>	Terminated with $50\Omega$ to $V_{CCOx}^{[b]}$	$V_{CCOx}^{[b]} - 0.50$		$V_{CCOx}^{[b]}-0.30$	V
V <sub>OUT</sub>	Output voltage swing	Qx, nQx <sup>[a]</sup>	- GCOX	300		500	mV

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

b. Outputs terminated with  $50\Omega$  to  $V_{CCOx}$  – 2V when  $V_{CCOx}$  = 3.3V ±5% or 2.5V ±5%. Outputs terminated with  $50\Omega$  to ground when  $V_{CCOx}$  = 1.8V ±5%.

c. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

b.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}$ .



# Table 20: CML (800mV Swing) DC and AC Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{CCOA}$ = $V_{CCOB}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{CCOA}$ = -40°C to +85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OH</sub>	Output high voltage	Qx, nQx <sup>[a]</sup>	T	V <sub>CCOx</sub> <sup>[b]</sup> – 0.10		V <sub>CCOx</sub>	V
V <sub>OL</sub>	Output low voltage	Qx, nQx <sup>[a]</sup>	Terminated with $50\Omega$ to $V_{CCOx}^{[b]}$	V <sub>CCOx</sub> <sup>[b]</sup> – 0.95		$V_{\rm CCOx}^{\rm [b]}-0.70$	V
V <sub>OUT</sub>	Output voltage swing	Qx, nQx <sup>[a]</sup>	000%	575		1000	mV

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

# Table 21: LVCMOS Clock Outputs DC Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{EE}$ = 0V, $T_A$ = -40°C to +85°C

		Test	V <sub>cco</sub>	A = 3.3	V±5%	V <sub>cco</sub>	A = 2.5	V±5%	V <sub>cco</sub>	A = 1.8	V ±5%	V <sub>cco</sub>	A = 1.5	V ±5%	
Symbol	Parameter	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Units
V <sub>OH</sub>	Output high voltage QAx, nQAx <sup>[a]</sup>	I <sub>OH</sub> = -8mA	2.6			1.1			1.1			1.1			V
V <sub>OL</sub>	Output low voltage QAx, nQAx <sup>[a]</sup>	I <sub>OL</sub> = 8mA			0.5			0.5			0.5			0.5	V

a. QAm denotes QA0, QA1, QA2, QA3. nQAm denotes nQA0, nQA1, nQA2, nQA3.

#### Table 22: Input Frequency Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $T_A$ = -40°C to +85°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>IN</sub>	Input frequency,	LVPECL,LVDS, HCSL, CML		1PPS		700MHz	
	CLKx, nCLKx	LVCMOS		1PPS		200MHz	
idc	Input duty cycle <sup>[a]</sup>				50		%
t	Carial part alask CCLK	I <sup>2</sup> C operation		100		400	kHz
†SCLK	Serial port clock SCLK	SPI operation				50	MHz

a. Any deviation from a 50% duty cycle on the input may be reflected in the output duty cycle.

b.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}$ .



### **AC Electrical Characteristics**

Table 23: AC Characteristics,  $V_{CC}$  = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%,  $V_{CCOA}$  =  $V_{CCOB}$  = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%,  $T_A$  = -40°C to +85°C

Symbol	Parame	ter <sup>[a]</sup>	Test	Conditions	Minimum	Typical	Maximum	Units			
		LVPECL, LVDS			4000		7001411				
f <sub>OUT</sub>	Output frequency	HCSL, CML <sup>[b]</sup>			1PPS		700MHz				
		LVCMOS			1PPS		200MHz				
			VCCOx = 1.8V ±	5%	0.85	1.90	2.70				
		LVPECL	VCCOx = 2.5V ±	5%	1.10	1.78	2.50	ns			
			VCCOx = 3.3V ±	5%	1.25	1.75	2.30				
		LVDS	VCCOx = 1.8V ±	5%	0.72	1.90	2.85				
			VCCOx = 2.5V ±	VCCOx = 2.5V ±5%			2.30	ns			
			VCCOx = 3.3V ±	5%	1.25	1.75	2.30				
	t <sub>PD</sub> Propagation Delay		VCCOx = 1.8V ±	5%	0.71	1.90	2.80				
		HCSL	VCCOx = 2.5V ±	5%	1.30	1.85	2.35	ns			
			VCCOx = 3.3V ±	5%	1.30	1.80	2.35				
t <sub>PD</sub>		Propagation Delay		VCCOx = 1.8V ±	5%	1.25	1.80	2.35			
		CML_800mV	VCCOx = 2.5V ±	1.30	1.75	2.15	ns				
			VCCOx = 3.3V ±	5%	1.30	1.70	2.10				
			VCCOx = 1.8V ±	5%	1.15	1.85					
		CML_400mV	VCCOx = 2.5V ±	5%	1.00	1.75	2.40	ns			
			VCCOx = 3.3V ±	1.00	1.70	2.40					
			VCCOx = 1.5V ±	1.80	2.85	4.45					
		LVOMOS	VCCOx = 1.8V ±	1.85	2.45	3.75	ns				
		LVCMOS	VCCOx = 2.5V ±	1.70	2.25	4.70					
			VCCOx = 3.3V ±	5%	1.60	2.20	2.85				
		LVPECL	20% to 80%		125		700	ps			
			$V_{CCOx}^{[c]} = 3.3V$	20% to 80%	105		550				
		LVDS	$V_{CCOx}^{[c]} = 2.5V$	20% to 80%	125		550	ps			
			$V_{CCOx}^{[c]} = 1.8V$	20% to 80%	175		550	ps			
1 /1	Output rise and fall	CML, 400mV	20% to 80%		100		675	ps			
t <sub>R</sub> / t <sub>F</sub>	times	CML, 800mV	20% to 80%		125		825	ps			
			V <sub>CCOA</sub> = 3.3V	20% to 80%							
		LVCMOS	V <sub>CCOA</sub> = 2.5V	20% to 80%	200		800	ps			
		LVCMOS	V <sub>CCOA</sub> = 1.8V	20% to 80%							
			V <sub>CCOA</sub> = 1.5V	20% to 80%		650	1300	ps			



Table 23: AC Characteristics,  $V_{CC}$  = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%,  $V_{CCOA}$  =  $V_{CCOB}$  = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%,  $T_A$  = -40°C to +85°C (Cont.)

Symbol	Parame	ter <sup>[a]</sup>	Test	Conditions	Minimum	Typical	Maximum	Units
		LVPECL				15	50	ps
		LVDS				20	60	ps
t <sub>sk</sub> (b)	Bank skew <sup>[d], [e], [f]</sup>	CML				10	35	ps
		HCSL				10	35	ps
		LVCMOS				50	100	ps
	Output duty cycle <sup>[g]</sup>	LVPECL,LVDS, HCSL, CML	Even divide ratio	os	45	50	55	%
		LVPECL,LVDS, HCSL, CML	Odd divide ratios	s / bypass	43	50	57	%
ada			2 2 2 4	Even divide ratios	45	50	55	%
odc		LVCMOS	V <sub>CCOA</sub> = 3.3V, 2.5V, or 1.8V	Odd divide ratios / bypass	40	50	60	%
				Even divide ratios	40	50	60	%
		LVCMOS V <sub>CCOA</sub> = 1.5V	V <sub>CCOA</sub> = 1.5V	Odd divide ratios / bypass	38	50	62	%
MUX <sub>ISOL</sub>	Mux isolation		156.25MHz, V <sub>SWING</sub> = 800mV			61		dB
	Noise floor		Offset >10MHz f		-154		dBc/Hz	

a. Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

- b. CML denotes CML 400mV and CML 800mV, unless otherwise stated.
- c. V<sub>CCOx</sub> denotes V<sub>CCOA</sub> and V<sub>CCOB</sub>.
- d. This parameter is guaranteed by characterization. Not tested in production.
- e. This parameter is defined in accordance with JEDEC Standard 65.
- f. Defined as skew within a bank of outputs at the same supply voltage and with equal load conditions.
- g. Measured using 50% duty cycle on input reference.



## Table 24: HCSL AC Characteristics, $V_{CC}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $V_{CCOA}$ = $V_{CCOB}$ = 3.3V ±5%, 2.5V ±5% or 1.8V ±5%, $T_A$ = -40°C to +85°C

Symbol	Parameter <sup>[a]</sup>	Test Conditions <sup>[b]</sup>	Minimum	Typical	Maximum	Units
+	Rise/ fall edge rate <sup>[c]</sup>	V <sub>CCOx</sub> = 3.3V or 2.5V	0.6		4	V/ns
t <sub>SLEW</sub>	Nise/ fall edge rate-	V <sub>CCOx</sub> = 1.8V	0.45		4	V/ns
V <sub>MAX</sub>	Absolute max. output voltage <sup>[d], [e]</sup>	V <sub>CCOx</sub> = 3.3V, 2.5V, 1.8V			1150	mV
V <sub>MIN</sub>	Absolute min. output voltage <sup>[d], [f]</sup>	V <sub>CCOx</sub> = 3.3V, 2.5V, 1.8V	-150			mV
V <sub>CROSS</sub>	Absolute crossing voltage <sup>[g], [h]</sup>	V <sub>CCOx</sub> = 3.3V, 2.5V, 1.8V			550	mV
$\Delta V_{ ext{CROSS}}$	Total variation of V <sub>CROSS</sub> over all edges <sup>[g], [i]</sup>	V <sub>CCOx</sub> = 3.3V, 2.5V, 1.8V			140	mV

- a. Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.
- b. V<sub>CCOx</sub> denotes V<sub>CCOA</sub> and V<sub>CCOB</sub>.
- c. Measured from –150mV to +150mV on the differential waveform (derived from Qx minus nQx). The signal must be monotonic through the measurement region for rise and fall time. The 300mV measurement window is centered on the differential zero crossing.
- d. Measurement taken from single ended waveform.
- e. Defined as the maximum instantaneous voltage including overshoot.
- f. Defined as the minimum instantaneous voltage including undershoot.
- g. Measured at crossing point where the instantaneous voltage value of the rising edge of Qm equals the falling edge of nQm.
- h. Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.
- i. Defined as the total variation of all crossing voltages of rising Qm and falling nQm, This is the maximum allowed variance in V<sub>CROSS</sub> for any particular system.



# Table 25: Additive Jitter, $V_{CC}$ = 3.3V, 2.5V or 1.8V, $V_{CCOA}$ = $V_{CCOB}$ = 3.3V, 2.5V, 1.8V or 1.5V (1.5V only supported for LVCMOS outputs), $T_A$ = 25°C

Symbol	Parameto	er	Т	est Conditions <sup>[a]</sup>	Minimum	Typical	Maximum	Units
			f <sub>OUT</sub> =	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		77	92	fs
		LVPECL	156.25MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		90	117	fs
			f <sub>OUT</sub> =	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		50	60	fs
			625MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		60	84	fs
			f <sub>OUT</sub> =	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		85	104 fs 6 185 fs 61 fs 84 fs	fs
		LVDS	156.25MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		126		fs
	RMS additive jitter (random); Integration range: 12kHz – 20MHz	LVDS	f <sub>OUT</sub> = 625MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		48	61	fs
t <sub>jit</sub> (f)				V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		57	84	fs
			f <sub>OUT</sub> =	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		92	132	fs
		HCSL	156.25MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		92	133	fs
		TIOSE	f <sub>OUT</sub> =	V <sub>CCOx</sub> <sup>[b]</sup> = 3.3V or 2.5V		61	73	fs
			625MHz	V <sub>CCOx</sub> <sup>[b]</sup> = 1.8V		67	93	fs
		LVCMOS		V <sub>CCOA</sub> = 3.3V or 2.5V		98	166	fs
			f <sub>OUT</sub> = 156.25MHz	V <sub>CCOA</sub> = 1.8V		128	204	fs
				V <sub>CCOA</sub> = 1.5V		198	314	fs

a. All outputs configured for the specific output type, as shown in the table.

b.  $V_{CCOx}$  denotes  $V_{CCOA}$  and  $V_{CCOB}$ .



## **Applications Information**

#### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **CLK/nCLK Inputs**

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from CLK to ground.

#### **LVCMOS Control Pins**

All control pins have internal pullups and pulldowns; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **Outputs:**

#### **LVCMOS Outputs**

All unused LVCMOS outputs can be left floating. It is recommended that there is no trace attached.

#### **LVPECL Outputs**

All unused LVPECL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

#### **LVDS Outputs**

All unused LVDS output pairs can be either left floating or terminated with  $100\Omega$  across. If they are left floating, there should be no trace attached.

#### **Differential Outputs**

All unused Differential outputs can be left floating. It is recommended that there is no trace attached.

## **Power Dissipation and Thermal Considerations**

The 8P79818 is a multi-functional, high speed device that targets a wide variety of clock frequencies and applications. Since this device is highly programmable with a broad range of features and functionality, the power consumption will vary as each of these features and functions is enabled.

The 8P79818 device was designed and characterized to operate within the ambient industrial temperature range of -40°C to +85°C. The ambient temperature represents the temperature around the device, not the junction temperature. When using the device in extreme cases, such as maximum operating frequency and high ambient temperature, external air flow may be required in order to ensure a safe and reliable junction temperature. Extreme care must be taken to avoid exceeding 125°C junction temperature.

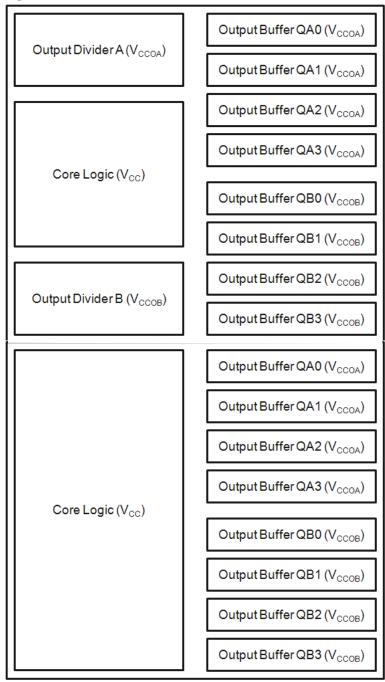
The power calculation examples below were generated using a maximum ambient temperature and supply voltage. For many applications, the power consumption will be much lower. Please contact Renesas technical support for any concerns on calculating the power dissipation for your own specific configuration.



#### **Power Domains**

The 8P79818 device has a number of separate power domains that can be independently enabled and disabled via register accesses (all power supply pins must still be connected to a valid supply voltage). Figure 7 below indicates the individual domains and the associated power pins.

Figure 7: 8P79818 Power Domains





#### **Power Consumption Calculation**

Determining total power consumption involves several steps:

- 1.Determine the power consumption using maximum current values for core voltage from Table 11, Table 12 and Table 13, Page 17 for the appropriate case of how many dividers are enabled.
- 2. Determine the nominal power consumption of each enabled output path.
- a. This consists of a base amount of power that is independent of operating frequency, as shown in Table 27 through Table 43 (depending on the chosen output protocol).
- b. Then there is a variable amount of power that is related to the output frequency. This can be determined by multiplying the output frequency by the FQ\_Factor shown in Table 27 through Table 43.
- 3.All of the above totals are then summed.

#### **Example Calculations**

#### Table 26: Example 1. Common Customer Configuration (3.3V Core Voltage)

Bank	Configuration	Frequency (MHz)	V <sub>cco</sub>	
Bank A	LVDS	125	3.3V	
Bank B	LVDS	125	2.5V	

- Core supply current, I<sub>CC</sub> = 24.7mA (max.)
- Output supply current, Bank A = 0.06 \* 125 + 71.615 = 79.115mA
- Output supply current, Bank B = 0.06 \* 125 + 71.615 = 79.115mA
- Total device current = 24.7mA + 79.115mA + 79.115mA = 182.93mA
- Total device power = 3.465V \* 183.93mA = 633.934mW

With an ambient temperature of 85°C and no airflow, the junction temperature is:

$$T_1 = 85^{\circ}C + 35.23^{\circ}C/W * 0.634W = 107.3^{\circ}C$$



#### **Thermal Considerations**

Once the total power consumption has been determined, it is necessary to calculate the maximum operating junction temperature for the device under the environmental conditions it will operate in. Thermal conduction paths, air flow rate and ambient air temperature are factors that can affect this. The thermal conduction path refers to whether heat is to be conducted away via a heat-sink, via airflow or via conduction into the PCB through the device pads (including the ePAD). Thermal conduction data is provided for typical scenarios in Table 44, Page 30. Please contact Renesas for assistance in calculating results under other scenarios.

#### **Current Consumption Data and Equations**

**Table 27: 3.3V LVDS Output Calculation Table** 

LVDS	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.06	71.615

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 28: 2.5V LVDS Output Calculation Table** 

LVDS	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.06	71.544

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 29: 1.8V LVDS Output Calculation Table** 

LVDS	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.1	50.284

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 30: 3.3V LVPECL Output Calculation Table** 

LVPECL	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.05	53.475

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 31: 2.5V LVPECL Output Calculation Table** 

LVPECL	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.04	20.874

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 32: 1.8V LVPECL Output Calculation Table** 

LVPECL	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.04	19.962

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

**Table 33: 3.3V HCSL Output Calculation Table** 

HCSL	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.05	54.911

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.



## Table 34: 3.3V CML Output (400mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.03	51.889

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

## Table 35: 2.5V CML Output (400mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.02	49.220

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

## Table 36: 1.8V CML Output (400mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.02	47.326

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

## Table 37: 3.3V CML Output (800mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.02	51.474

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

## Table 38: 2.5V CML Output (800mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.02	48.906

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

## Table 39: 1.8V CML Output (800mV) Calculation Table

CML	FQ_Factor (mA/MHz), per output	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	0.02	47.334

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

#### **Table 40: 3.3V LVCMOS Output Calculation Table**

LVCMOS	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	62.289

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

#### **Table 41: 2.5V LVCMOS Output Calculation Table**

LVCMOS	Base_Current (mA)
Qx, nQx <sup>[a]</sup>	51.097

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

#### **Table 42: 1.8V LVCMOS Output Calculation Table**

LVCMOS	Base_Current (mA)	
Qx, nQx <sup>[a]</sup>	47.745	

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3. nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.

#### **Table 43: 1.5V LVCMOS Output Calculation Table**

LVCMOS	Base_Current (mA)	
Qx, nQx <sup>[a]</sup>	41.485	

a. Qx denotes QA0, QA1, QA2, QA3, QB0, QB1, QB2, QB3.
 nQx denotes nQA0, nQA1, nQA2, nQA3, nQB0, nQB1, nQB2, nQB3.



Applying the values to the following equation will yield output current by frequency: (mA) = FQ\_Factor \* Frequency (MHz) + Base\_Current where:

Qx Current is the specific output current according to output type and frequency

FQ\_Factor is used for calculating current increase due to output frequency

Base\_Current is the base current for each output path independent of output frequency

The second step is to multiply the power dissipated by the thermal impedance to determine the maximum power gradient, using the following equation:

$$T_J = T_A + (\theta_{JA} * Pd_{total})$$

where:

T<sub>J</sub> is the junction temperature (°C)

T<sub>A</sub> is the ambient temperature (°C)

θ<sub>JA</sub> is the thermal resistance value from Table 44, Page 30, dependent on ambient airflow (°C/W)

Pd<sub>total</sub> is the total power dissipation of the 8P79818 under usage conditions, including power dissipated due to loading (W)

Note that for LVPECL outputs the power dissipation through the load is assumed to be 27.95mW. When selecting LVCMOS outputs, power dissipation through the load will vary based on a variety of factors including termination type and trace length. For these examples, power dissipation through loading will be calculated using C<sub>PD</sub> (found in Table 10, Page 15) and output frequency:

$$Pd_{OUT} = C_{PD} * f_{OUT} * V_{CCO}^2$$

where:

Pd<sub>out</sub> is the power dissipation of the output (W)

C<sub>PD</sub> is the power dissipation capacitance (pF)

f<sub>OUT</sub> is the output frequency of the selected output (MHz)

V<sub>CCO</sub> is the voltage supplied to the appropriate output (V)

### Table 44: $\theta_{\text{JA}}$ vs. Air Flow Table for a 32-lead 5mm x 5mm VFQFN

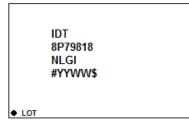
$\theta_{JA}$ vs. Air Flow			
Meters per Second	0	1	2
Multi-Layer PCB, JEDEC Standard Test Boards	35.23°C/W	31.6°C/W	30.0°C/W



## **Package Outline Drawings**

The package outline drawings are located at the end of this document and are accessible from the Renesas website (see Ordering Information for POD links). The package information is the most current data available and is subject to change without revision of this document.

## **Marking Diagram**



- Line 1 is the prefix of the part number.
- Line 2 and Line 3 is the part number.
- Line 4:
  - "#" denotes the stepping number.
  - "YY" are the last digits of the year and "WW" is the work week that the part was assembled.
  - "\$" denotes mark code.

## **Ordering Information**

#### **Table 45: Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8P79818NLGI	IDT8P79818NLGI		Tray	-40°C to +85°C
8P79818NLGI8	IDT8P79818NLGI	32-lead VFQFN, Lead Free	Tape & Reel	-40°C to +85°C
8P79818NLGI/W	IDT8P79818NLGI		Tape & Reel	-40°C to +85°C

Table 46: Pin 1 Orientation in Tape and Reel Packaging

Part Number Suffix	Pin 1 Orientation	Illustration
NLGI8	Quadrant 1 (EIA-481-C)	Correct Pin 1 ORIENTATION  CARRIER TAPE TOPSIDE (Round Sprocket Holes)  USER DIRECTION OF FEED
NLGI/W	Quadrant 2 (EIA-481-D)	Correct Pin 1 ORIENTATION CARRIER TAPE TOPSIDE (Round Sprocket Holes)  USER DIRECTION OF FEED



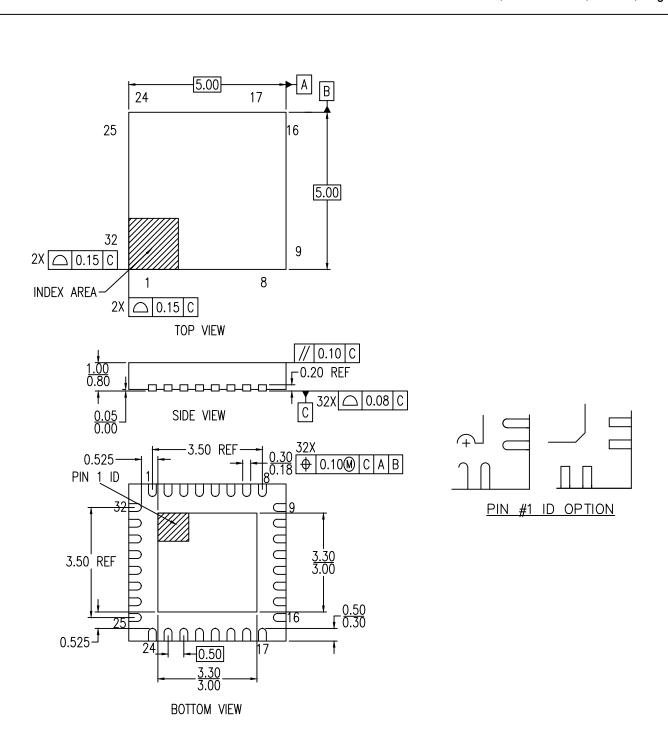
## **Revision History**

Revision Date	Description of Change	
July 29, 2021	Added output voltage swing in Table 17.	
June 25, 2021	<ul> <li>Added propagation delay specifications to AC Characteristics table.</li> <li>Updated Package Outline Drawings section.</li> <li>Rebranded datasheet.</li> </ul>	
December 19, 2016	Initial datasheet.	



## 32-VFQFPN, Package Outline Drawing

5.0 x 5.0 x 0.90 mm Body, Epad 3.15 x 3.15 mm. NLG32P1, PSC-4171-01, Rev 02, Page 1



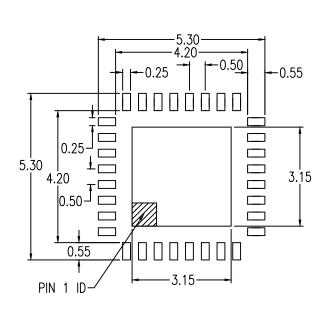
#### NOTE:

- 1. ALL DIMENSION ARE IN MM. ANGLES IN DEGREES.
- 2. COPLANARITY APPLIE TO THE EXPOSED PAD AS WELL AS THE TERMINALS. COPLANARITY SHALL NOT EXCEED 0.08 MM.
- 3. WARPAGE SHALL NOT EXCEED 0.10 MM.
- 4. PIN LOCATION IS UNDENTIFIED BY EITHER CHAMFER OR NOTCH.



## 32-VFQFPN, Package Outline Drawing

5.0 x 5.0 x 0.90 mm Body, Epad 3.15 x 3.15 mm. NLG32P1, PSC-4171-01, Rev 02, Page 2



#### RECOMMENDED LAND PATTERN DIMENSION

- 1. ALL DIMENSIONS ARE IN MM. ANGLES IN DEGREES. 2. TOP DOWN VIEW. AS VIEWED ON PCB.
- 3. LAND PATTERN RECOMMENDATION PER IPC-7351B GENERIC REQUIREMENT FOR SURFACE MOUNT DESIGN AND LAND PATTERN.

Package Revision History		
Date Created Rev No. Description		
April 12, 2018	Rev 02	New Format
Feb 8, 2016	Rev 01	Added "k: Value

#### IMPORTANT NOTICE AND DISCLAIMER

RENESAS ELECTRONICS CORPORATION AND ITS SUBSIDIARIES ("RENESAS") PROVIDES TECHNICAL SPECIFICATIONS AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS OR IMPLIED, INCLUDING, WITHOUT LIMITATION, ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for developers skilled in the art designing with Renesas products. You are solely responsible for (1) selecting the appropriate products for your application, (2) designing, validating, and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. Renesas grants you permission to use these resources only for development of an application that uses Renesas products. Other reproduction or use of these resources is strictly prohibited. No license is granted to any other Renesas intellectual property or to any third party intellectual property. Renesas disclaims responsibility for, and you will fully indemnify Renesas and its representatives against, any claims, damages, costs, losses, or liabilities arising out of your use of these resources. Renesas' products are provided only subject to Renesas' Terms and Conditions of Sale or other applicable terms agreed to in writing. No use of any Renesas resources expands or otherwise alters any applicable warranties or warranty disclaimers for these products.

(Rev.1.0 Mar 2020)

#### **Corporate Headquarters**

TOYOSU FORESIA, 3-2-24 Toyosu, Koto-ku, Tokyo 135-0061, Japan www.renesas.com

#### **Trademarks**

Renesas and the Renesas logo are trademarks of Renesas Electronics Corporation. All trademarks and registered trademarks are the property of their respective owners.

#### **Contact Information**

For further information on a product, technology, the most up-to-date version of a document, or your nearest sales office, please visit:

www.renesas.com/contact/

## **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Clock Buffer category:

Click to view products by Renesas manufacturer:

Other Similar products are found below:

MPC962309EJ-1H NB4N121KMNG IDT49FCT805ASO MK2308S-1HILF PL133-27GI-R NB3L02FCT2G NB3L03FCT2G
ZL40203LDG1 ZL40200LDG1 ZL40205LDG1 9FG1200DF-1LF 9FG1001BGLF ZL40202LDG1 PI49FCT20802QE SL2305SC-1T
PI6C4931502-04LIE NB7L1008MNG NB7L14MN1G PI49FCT20807QE PI6C4931502-04LIEX ZL80002QAB1 PI6C4931504-04LIEX
PI6C10806BLEX ZL40226LDG1 ZL40219LDG1 8T73S208B-01NLGI SY75578LMG PI49FCT32805QEX PL133-27GC-R
MC10LVEP11DG MC10EP11DTG MC100LVEP11DG MC100E111FNG MC100EP11DTG NB6N11SMNG NB7L14MMNG
NB6L11MMNG NB6L14MMNR2G NB6L611MNG PL123-02NGI-R NB3N111KMNR4G ADCLK944BCPZ-R7 ZL40217LDG1
NB7LQ572MNG HMC940LC4BTR ADCLK946BCPZ-REEL7 ADCLK946BCPZ ADCLK846BCPZ-REEL7 ADCLK854BCPZ-REEL7
ADCLK905BCPZ-R2